



**THE DATASHEET OF
TLV5625IDRG4**



TLV5625

2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

features

- Dual 8-Bit Voltage Output DAC
- Programmable Internal Reference
- Programmable Settling Time
 - 3 μ s in Fast Mode
 - 10 μ s in Slow Mode
- Compatible With TMS320 and SPI™ Serial Ports
- Differential Nonlinearity <0.2 LSB Max
- Monotonic Over Temperature

applications

- Digital Servo Control Loops
- Digital Offset and Gain Adjustment
- Industrial Process Control
- Machine and Motion Control Devices
- Mass Storage Devices

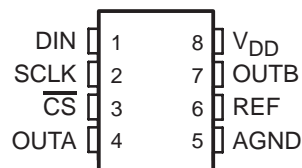
description

The TLV5625 is a dual 8-bit voltage output DAC with a flexible 3-wire serial interface. The serial interface is compatible with TMS320, SPI™, QSPI™, and Microwire™ serial ports. It is programmed with a 16-bit serial string containing 4 control and 8 data bits.

The resistor string output voltage is buffered by an x2 gain rail-to-rail output buffer. The buffer features a Class-AB output stage to improve stability and reduce settling time. The programmable settling time of the DAC allows the designer to optimize speed versus power dissipation.

Implemented with a CMOS process, the device is designed for single supply operation from 2.7 V to 5.5 V. It is available in an 8-pin SOIC package in standard commercial and industrial temperature ranges.

D PACKAGE
(TOP VIEW)



AVAILABLE OPTIONS

T _A	PACKAGE
	SOIC (D)
0°C to 70°C	TLV5625CD
–40°C to 85°C	TLV5625ID



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

SPI and QSPI are trademarks of Motorola, Inc.
Microwire is a trademark of National Semiconductor Corporation.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



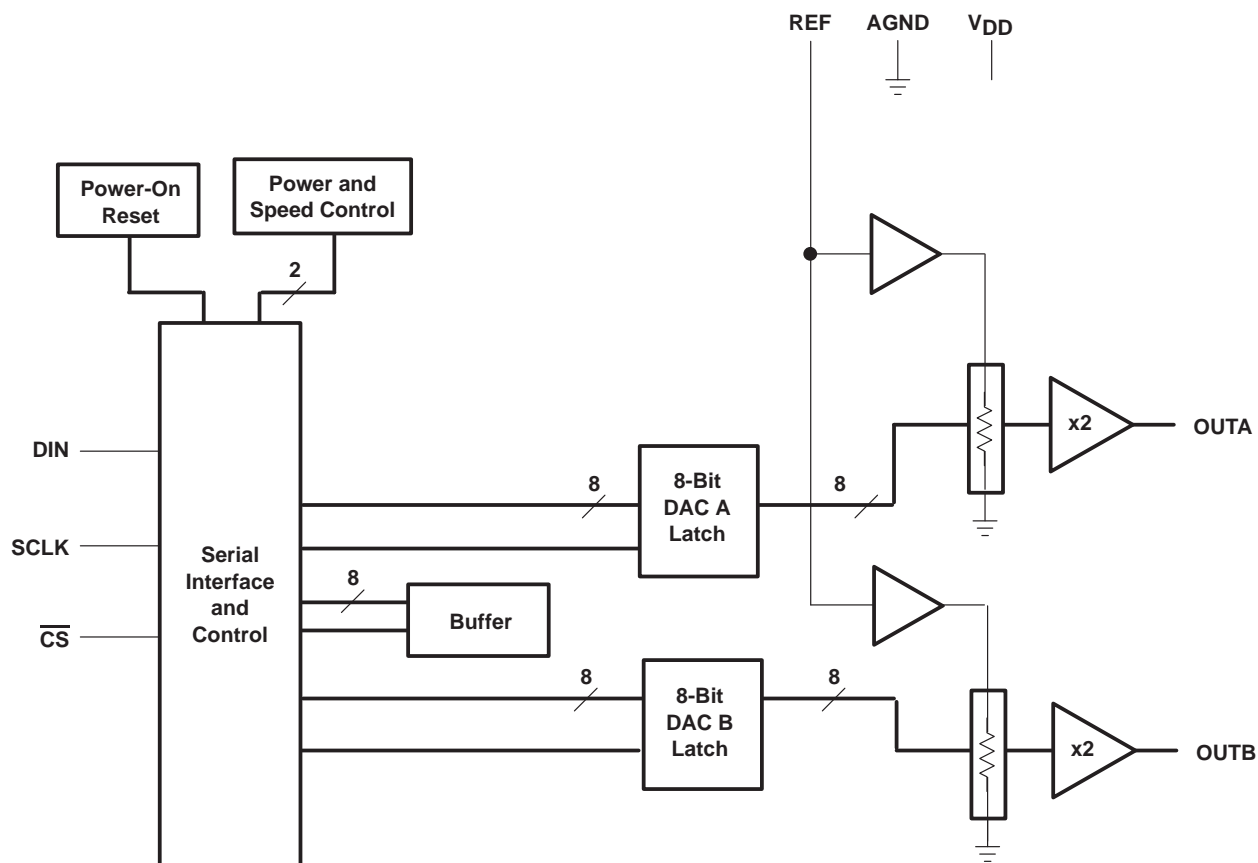
POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

Copyright © 2002, Texas Instruments Incorporated

TLV5625
2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG
CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

functional block diagram



Terminal Functions

TERMINAL NAME	NO.	I/O/P	DESCRIPTION
AGND	5	P	Ground
$\overline{\text{CS}}$	3	I	Chip select. Digital input active low, used to enable/disable inputs.
DIN	1	I	Digital serial data input
OUTA	4	O	DAC A analog voltage output
OUTB	7	O	DAC B analog voltage output
REF	6	I	Analog reference voltage input
SCLK	2	I	Digital serial clock input
VDD	8	P	Positive power supply

TLV5625

2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage (V_{DD} to AGND)	7 V
Reference input voltage range	– 0.3 V to $V_{DD} + 0.3$ V
Digital input voltage range	– 0.3 V to $V_{DD} + 0.3$ V
Operating free-air temperature range, T_A : TLV5625C	0°C to 70°C
TLV5625I	–40°C to 85°C
Storage temperature range, T_{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V_{DD}	$V_{DD} = 5$ V	4.5	5	5.5	V
	$V_{DD} = 3$ V	2.7	3	3.3	
Power on reset, POR		0.55		2	V
High-level digital input voltage, V_{IH}	$V_{DD} = 2.7$ V	2			V
	$V_{DD} = 5.5$ V	2.4			
Low-level digital input voltage, V_{IL}	$V_{DD} = 2.7$ V			0.6	V
	$V_{DD} = 5.5$ V			1	
Reference voltage, V_{ref} to REF terminal	$V_{DD} = 5$ V (see Note 1)	AGND	2.048	$V_{DD} - 1.5$	V
	$V_{DD} = 3$ V (see Note 1)	AGND	1.024	$V_{DD} - 1.5$	V
Load resistance, R_L		2			k Ω
Load capacitance, C_L				100	pF
Clock frequency, f_{CLK}				20	MHz
Operating free-air temperature, T_A	TLV5625C	0		70	°C
	TLV5625I	–40		85	

NOTE 1: Due to the x2 output buffer, a reference input voltage $\geq (V_{DD} - 0.4$ V)/2 causes clipping of the transfer function.



2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

electrical characteristics over recommended operating conditions (unless otherwise noted)

power supply

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
I _{DD}	Power supply current	No load, All inputs = AGND or V _{DD} , DAC latch = 0x800	Fast	1.8	2.3	mA
			Slow	0.8	1	
	Power-down supply current			1	3	μA
PSRR	Power supply rejection ratio	Zero scale, See Note 2		-65		dB
		Full scale, See Note 3		-65		

NOTES: 2. Power supply rejection ratio at zero scale is measured by varying V_{DD} and is given by:

$$PSRR = 20 \log [(E_{ZS}(V_{DDmax}) - E_{ZS}(V_{DDmin})/V_{DDmax}]$$

3. Power supply rejection ratio at full scale is measured by varying V_{DD} and is given by:

$$PSRR = 20 \log [(E_G(V_{DDmax}) - E_G(V_{DDmin})/V_{DDmax}]$$

static DAC specifications

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Resolution		8			bits
INL	Integral nonlinearity	See Note 4		±0.3	±0.5	LSB
DNL	Differential nonlinearity	See Note 5		±0.07	±0.2	LSB
E _{ZS}	Zero-scale error (offset error at zero scale)	See Note 6			±12	mV
E _{ZS TC}	Zero-scale-error temperature coefficient	See Note 7		10		ppm/°C
E _G	Gain error	See Note 8			±0.5	% full scale V
E _{G TC}	Gain-error temperature coefficient	See Note 9		10		ppm/°C

NOTES: 4. The relative accuracy of integral nonlinearity (INL), sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale, excluding the effects of zero-code and full-scale errors.

5. The differential nonlinearity (DNL), sometimes referred to as differential error, is the difference between the measured and ideal 1-LSB amplitude change of any two adjacent codes.

6. Zero-scale error is the deviation from zero voltage output when the digital input code is zero.

7. Zero-scale error temperature coefficient is given by: $E_{ZS TC} = [E_{ZS}(T_{max}) - E_{ZS}(T_{min})]/2V_{ref} \times 10^6/(T_{max} - T_{min})$.

8. Gain error is the deviation from the ideal output (2V_{ref} - 1 LSB) with an output load of 10 kΩ.

9. Gain temperature coefficient is given by: $E_{G TC} = [E_G(T_{max}) - E_G(T_{min})]/2V_{ref} \times 10^6/(T_{max} - T_{min})$.

output specifications

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _O	Output voltage range	R _L = 10 kΩ	0	V _{DD} -0.4		V
	Output load regulation accuracy	V _O = 4.096 V, 2.048 V R _L = 2 kΩ			±0.29	% FS

reference input

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _I	Input voltage range		0	V _{DD} -1.5		V
R _I	Input resistance			10		MΩ
C _I	Input capacitance			5		pF
Reference input bandwidth	REF = 0.2 V _{pp} + 1.024 V dc	Fast		1.3		MHz
		Slow		525		kHz
Reference feedthrough	REF = 1 V _{pp} at 1 kHz + 1.024 V dc (see Note 10)			-80		dB

NOTE 10: Reference feedthrough is measured at the DAC output with an input code = 0x000.

TLV5625

2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

electrical characteristics over recommended operating conditions (unless otherwise noted)
(Continued)

digital inputs

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
I_{IH}	High-level digital input current	$V_I = V_{DD}$			1	μA
I_{IL}	Low-level digital input current	$V_I = 0 V$	-1			μA
C_i	Input capacitance			8		ρF

analog output dynamic performance

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{s(FS)}$	Output settling time, full scale	$R_L = 10 k\Omega$, See Note 11	$C_L = 100 \rho F$,	Fast	1	3	μs
				Slow	3	10	
$t_{s(CC)}$	Output settling time, code to code	$R_L = 10 k\Omega$, See Note 12	$C_L = 100 \rho F$,	Fast	1		μs
				Slow	2		
SR	Slew rate	$R_L = 10 k\Omega$, See Note 13	$C_L = 100 \rho F$,	Fast	3		$V/\mu s$
				Slow	0.5		
Glitch energy		$\overline{DIN} = 0$ to 1, $\overline{CS} = V_{DD}$	FCLK = 100 kHz,		5		$nV-s$
SNR	Signal-to-noise ratio	$f_s = 102$ kSPS, $f_{out} = 1$ kHz, $R_L = 10 k\Omega$, $C_L = 100 \rho F$		52	54		dB
SINAD	Signal-to-noise + distortion			48	49		
THD	Total harmonic distortion			-50	-48		
SFDR	Spurious free dynamic range			48	50		

- NOTES: 11. Settling time is the time for the output signal to remain within ± 0.5 LSB of the final measured value for a digital input code change of 0x020 to 0xFDF and 0xFDF to 0x020 respectively. Not tested, assured by design.
12. Settling time is the time for the output signal to remain within ± 0.5 LSB of the final measured value for a digital input code change of one count. Not tested, assured by design.
13. Slew rate determines the time it takes for a change of the DAC output from 10% to 90% of full-scale voltage.

TLV5625
2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG
CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

digital input timing requirements

	MIN	NOM	MAX	UNIT
$t_{su}(CS-CK)$ Setup time, \overline{CS} low before first negative SCLK edge	10			ns
$t_{su}(C16-CS)$ Setup time, 16 th negative SCLK edge before \overline{CS} rising edge	10			ns
t_{wH} SCLK pulse width high	25			ns
t_{wL} SCLK pulse width low	25			ns
$t_{su}(D)$ Setup time, data ready before SCLK falling edge	10			ns
$t_h(D)$ Hold time, data held valid after SCLK falling edge	10			ns

timing requirements

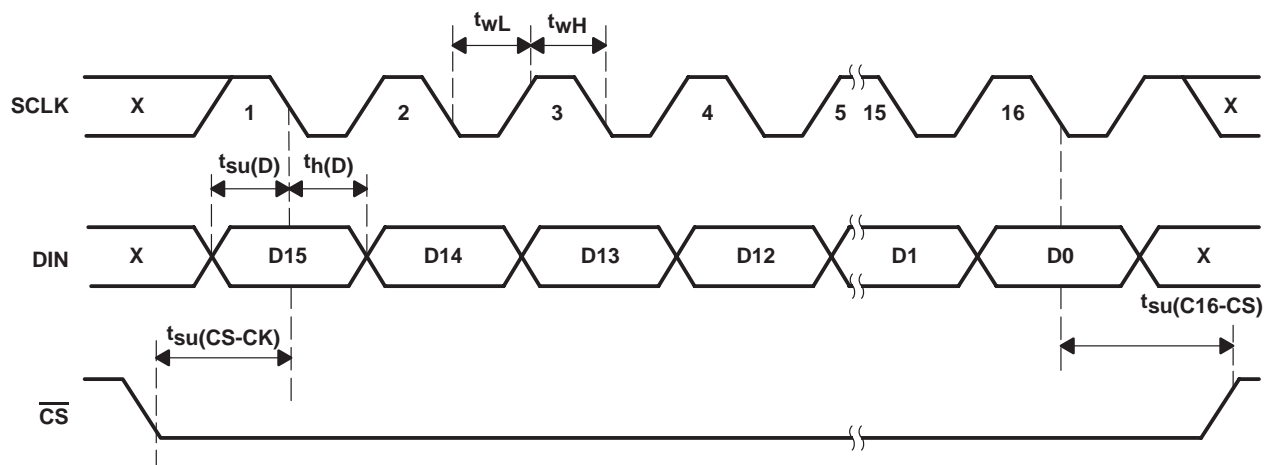


Figure 1. Timing Diagram

TLV5625

2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

TYPICAL CHARACTERISTICS

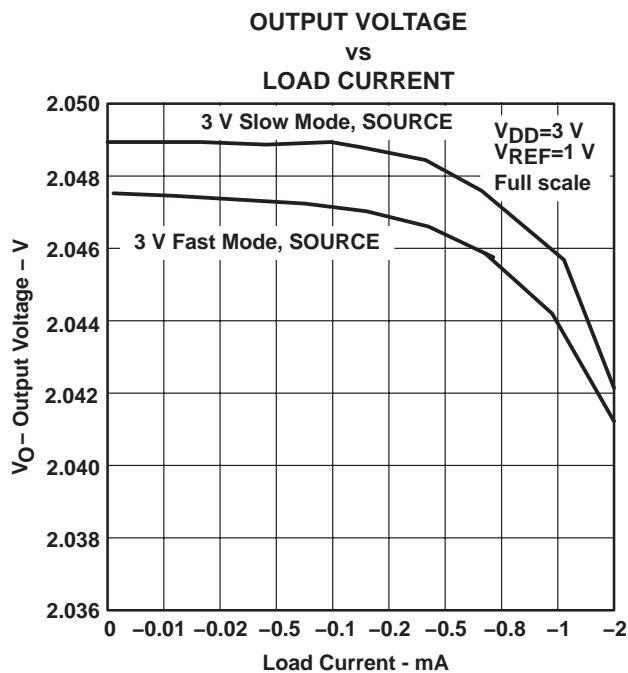


Figure 2

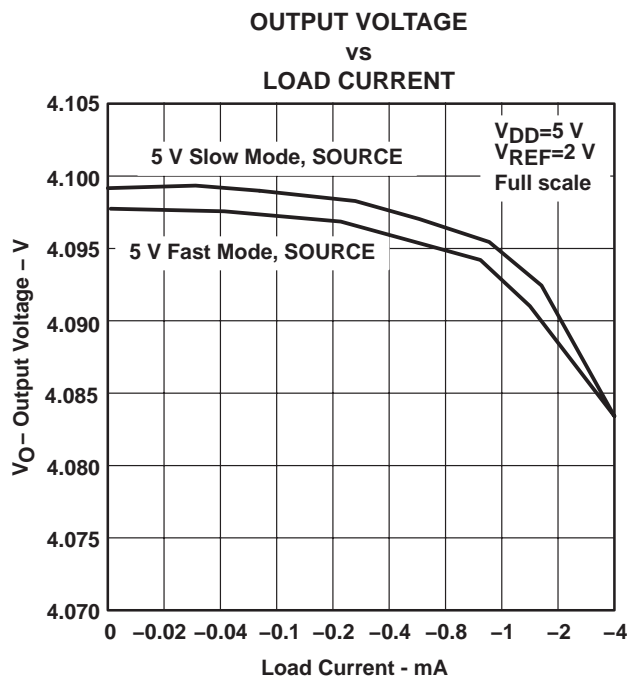


Figure 3

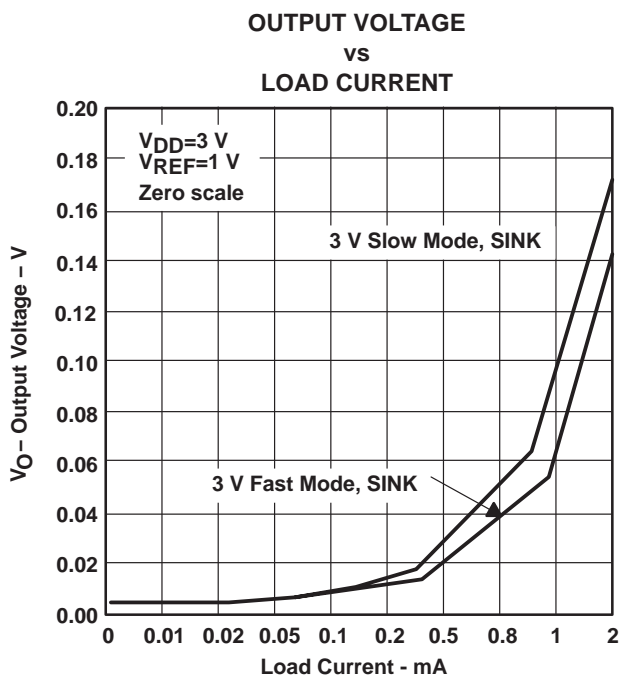


Figure 4

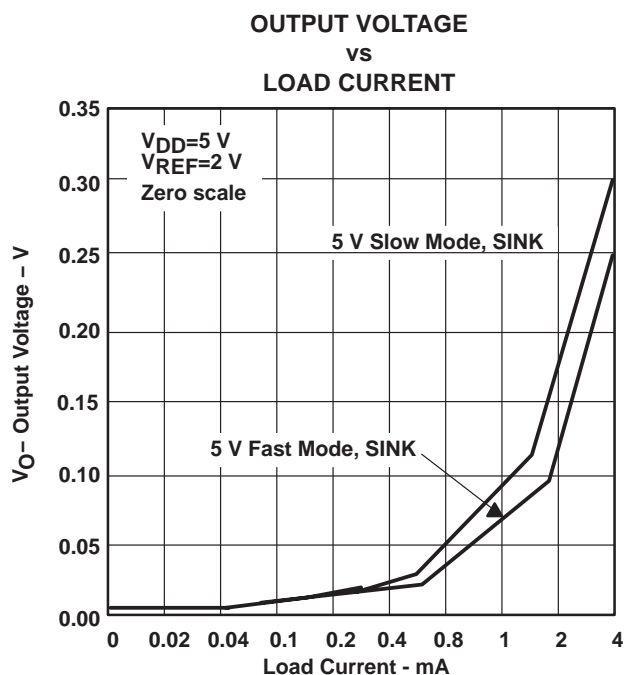


Figure 5

TLV5625
2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG
CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

TYPICAL CHARACTERISTICS

SUPPLY CURRENT
vs
FREE-AIR TEMPERATURE

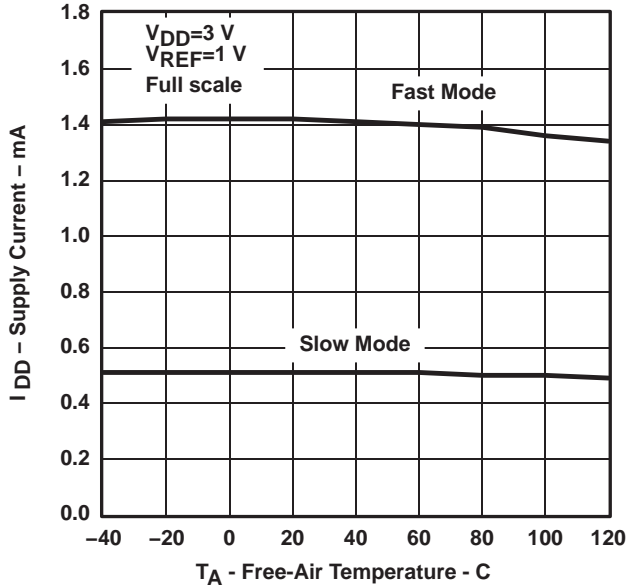


Figure 6

SUPPLY CURRENT
vs
FREE-AIR TEMPERATURE

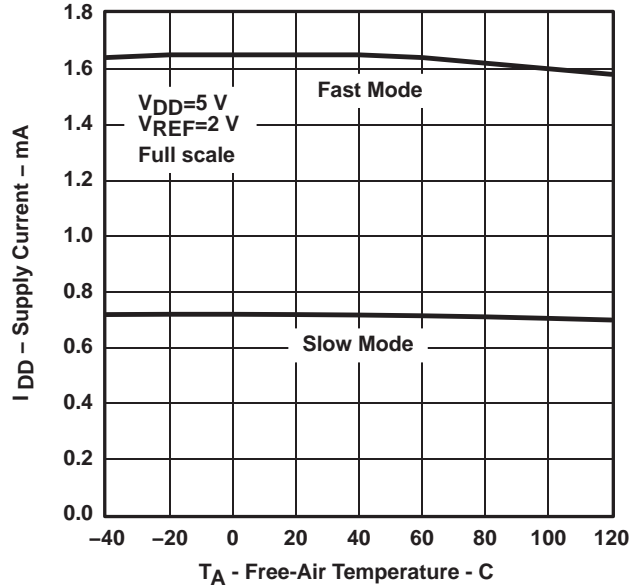


Figure 7

TOTAL HARMONIC DISTORTION
vs
FREQUENCY

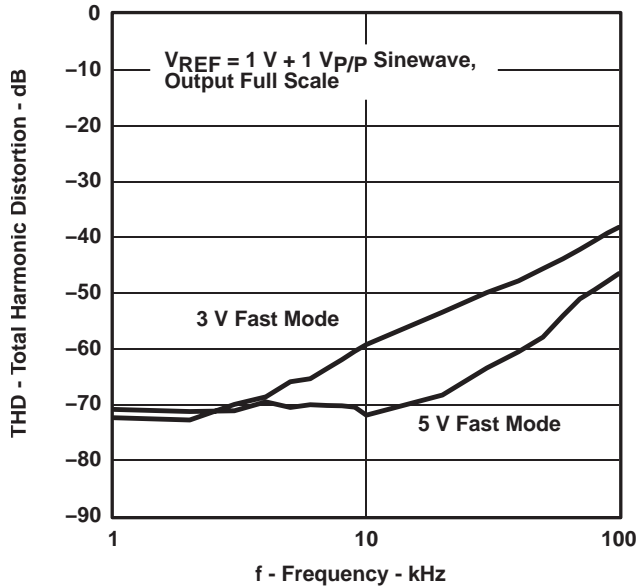


Figure 8

TOTAL HARMONIC DISTORTION
vs
FREQUENCY

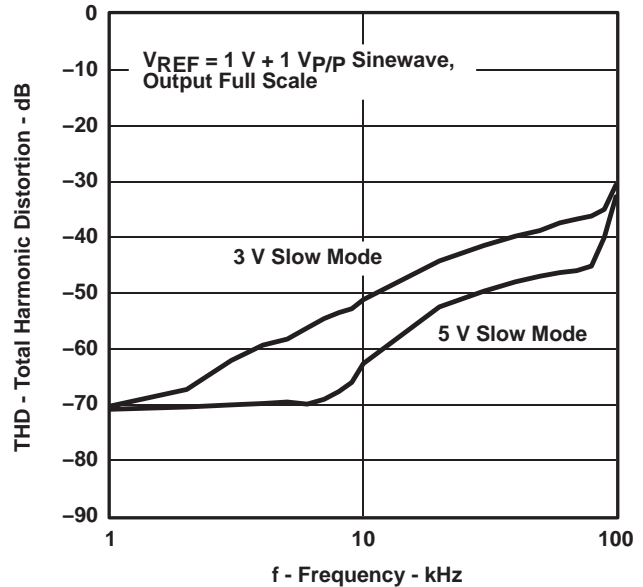


Figure 9



TYPICAL CHARACTERISTICS

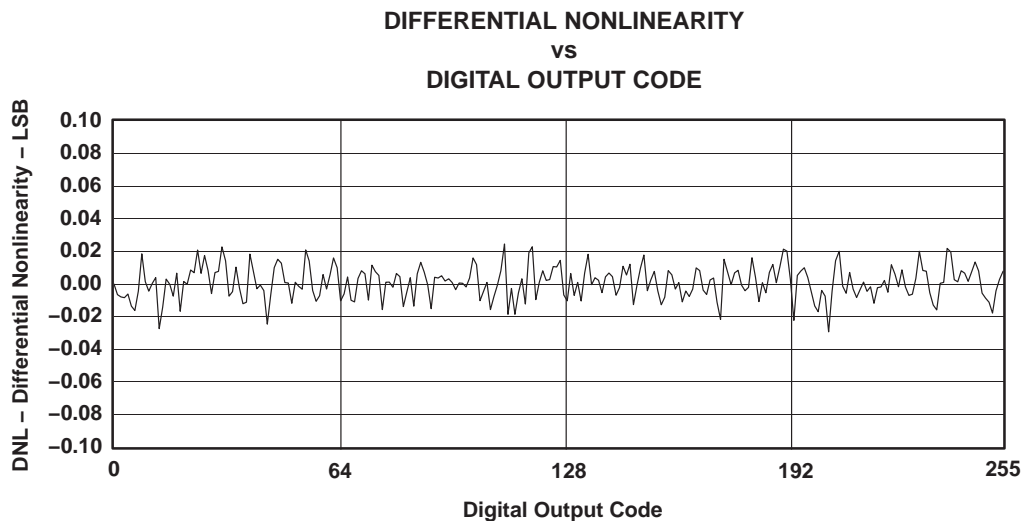


Figure 10

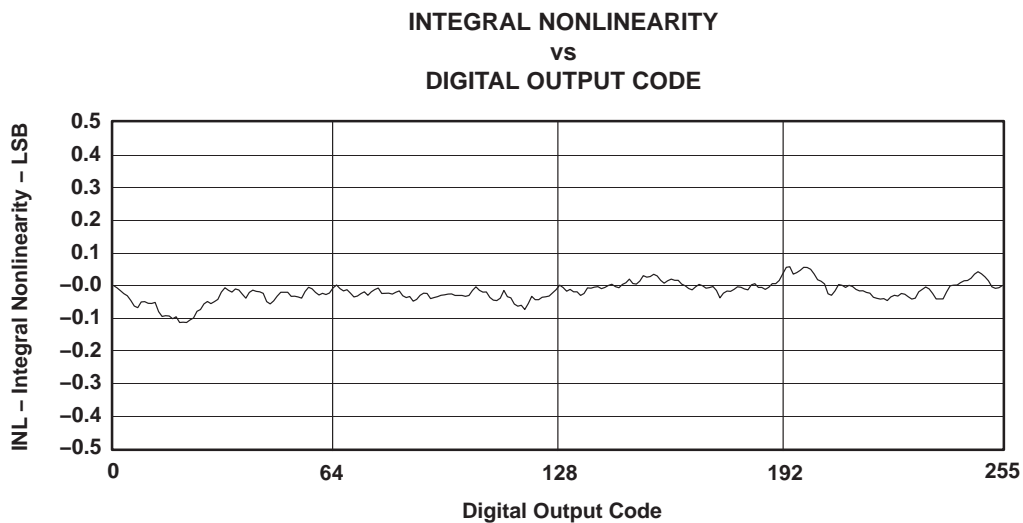


Figure 11

TLV5625

2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

APPLICATION INFORMATION

general function

The TLV5625 is a dual 8-bit, single-supply DAC, based on a resistor-string architecture. It consists of a serial interface, a speed and power-down control logic, a resistor string, and a rail-to-rail output buffer.

The output voltage (full scale determined by the reference) is given by:

$$2 \text{ REF} \frac{\text{CODE}}{2^n} \text{ [V]}$$

Where REF is the reference voltage and CODE is the digital input value within the range of 0_{10} to 2^n-1 , where $n=8$ (bits). The 16-bit data word, consisting of control bits and the new DAC value, is illustrated in the *data format* section. A power-on reset initially resets the internal latches to a defined state (all bits zero).

serial interface

A falling edge of $\overline{\text{CS}}$ starts shifting the data bit-per-bit (starting with the MSB) to the internal register on the falling edges of SCLK. After 16 bits have been transferred or $\overline{\text{CS}}$ rises, the content of the shift register is moved to the target latches (DAC A, DAC B, BUFFER, CONTROL), depending on the control bits within the data word.

Figure 2 shows examples of how to connect the TLV5625 to TMS320, SPI™, and Microwire™.

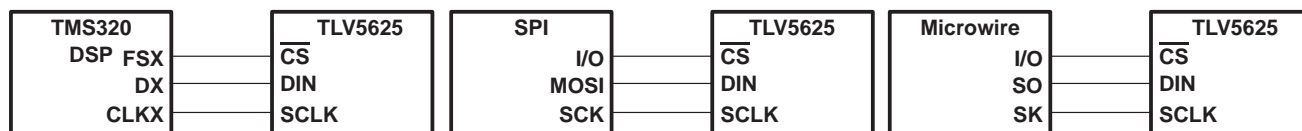


Figure 12. Three-Wire Interface

Notes on SPI™ and Microwire™: Before the controller starts the data transfer, the software has to generate a falling edge on the pin connected to $\overline{\text{CS}}$. If the word width is 8 bits (SPI™ and Microwire™) two write operations must be performed to program the TLV5625. After the write operation(s), the holding registers or the control register are updated automatically on the 16th positive clock edge.

serial clock frequency and update rate

The maximum serial clock frequency is given by:

$$f_{\text{sclkmax}} = \frac{1}{t_{\text{whmin}} + t_{\text{wlmin}}} = 20 \text{ MHz}$$

The maximum update rate is:

$$f_{\text{updatemax}} = \frac{1}{16(t_{\text{whmin}} + t_{\text{wlmin}})} = 1.25 \text{ MHz}$$

Note that the maximum update rate is just a theoretical value for the serial interface, as the settling time of the TLV5625 should also be considered.

TLV5625
2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG
CONVERTER WITH POWER DOWN

SLAS233D – JULY 1999 – REVISED JULY 2002

APPLICATION INFORMATION

examples of operation (continued)

Both outputs are updated on the rising clock edge after D0 from the DAC A data word is sampled.

- Set power-down mode:

D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
X	X	1	X	X	X	X	X	X	X	X	X	X	X	X	X

X = Don't care

linearity, offset, and gain error using single ended supplies

When an amplifier is operated from a single supply, the voltage offset can still be either positive or negative. With a positive offset, the output voltage changes on the first code change. With a negative offset, the output voltage may not change with the first code, depending on the magnitude of the offset voltage.

The output amplifier attempts to drive the output to a negative voltage. However, because the most negative supply rail is ground, the output cannot drive below ground and clamps the output at 0 V.

The output voltage then remains at zero until the input code value produces a sufficient positive output voltage to overcome the negative offset voltage, resulting in the transfer function shown in Figure 13.

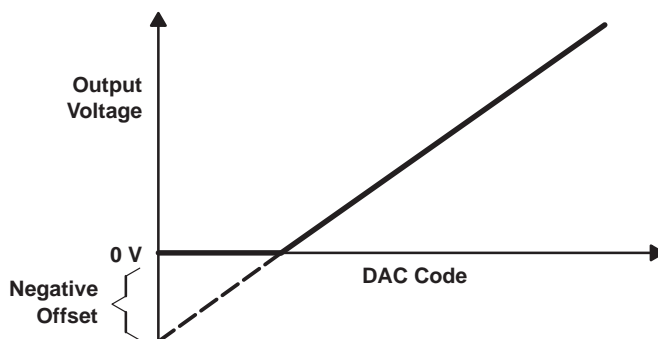


Figure 13. Effect of Negative Offset (Single Supply)

This offset error, not the linearity error, produces this breakpoint. The transfer function would have followed the dotted line if the output buffer could drive below the ground rail.

For a DAC, linearity is measured between zero-input code (all inputs 0) and full-scale code (all inputs 1) after offset and full scale are adjusted out or accounted for in some way. However, single supply operation does not allow for adjustment when the offset is negative due to the breakpoint in the transfer function. So the linearity is measured between full-scale code and the lowest code that produces a positive output voltage.

power-supply bypassing and ground management

Printed-circuit boards that use separate analog and digital ground planes offer the best system performance. Wire-wrap boards do not perform well and should not be used. The two ground planes should be connected together at the low-impedance power-supply source. The best ground connection may be achieved by connecting the DAC AGND terminal to the system analog ground plane, making sure that analog ground currents are well managed and there are negligible voltage drops across the ground plane.

A 0.1-μF ceramic-capacitor bypass should be connected between V_{DD} and AGND and mounted with short leads as close as possible to the device. Use of ferrite beads may further isolate the system analog supply from the digital power supply.

Figure 14 shows the ground plane layout and bypassing technique.



APPLICATION INFORMATION

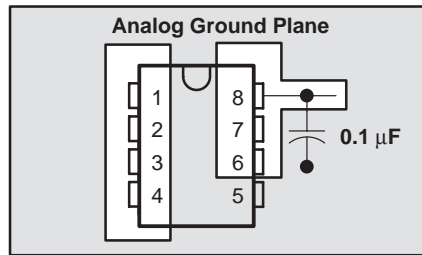


Figure 14. Power-Supply Bypassing

definitions of specifications and terminology

integral nonlinearity (INL)

The relative accuracy or integral nonlinearity (INL), sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors.

differential nonlinearity (DNL)

The differential nonlinearity (DNL), sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.

zero-scale error (E_{ZS})

Zero-scale error is defined as the deviation of the output from 0 V at a digital input value of 0.

gain error (E_G)

Gain error is the error in slope of the DAC transfer function.

signal-to-noise ratio + distortion (S/N+D)

S/N+D is the ratio of the rms value of the output signal to the rms sum of all other spectral components below the Nyquist frequency, including harmonics but excluding dc. The value for S/N+D is expressed in decibels.

spurious free dynamic range (SFDR)

SFDR is the difference between the rms value of the output signal and the rms value of the largest spurious signal within a specified bandwidth. The value for SFDR is expressed in decibels.

total harmonic distortion (THD)

THD is the ratio of the rms sum of the first six harmonic components to the rms value of the fundamental signal and is expressed in decibels.

TLV5625
2.7-V TO 5.5-V LOW-POWER DUAL 8-BIT DIGITAL-TO-ANALOG
CONVERTER WITH POWER DOWN

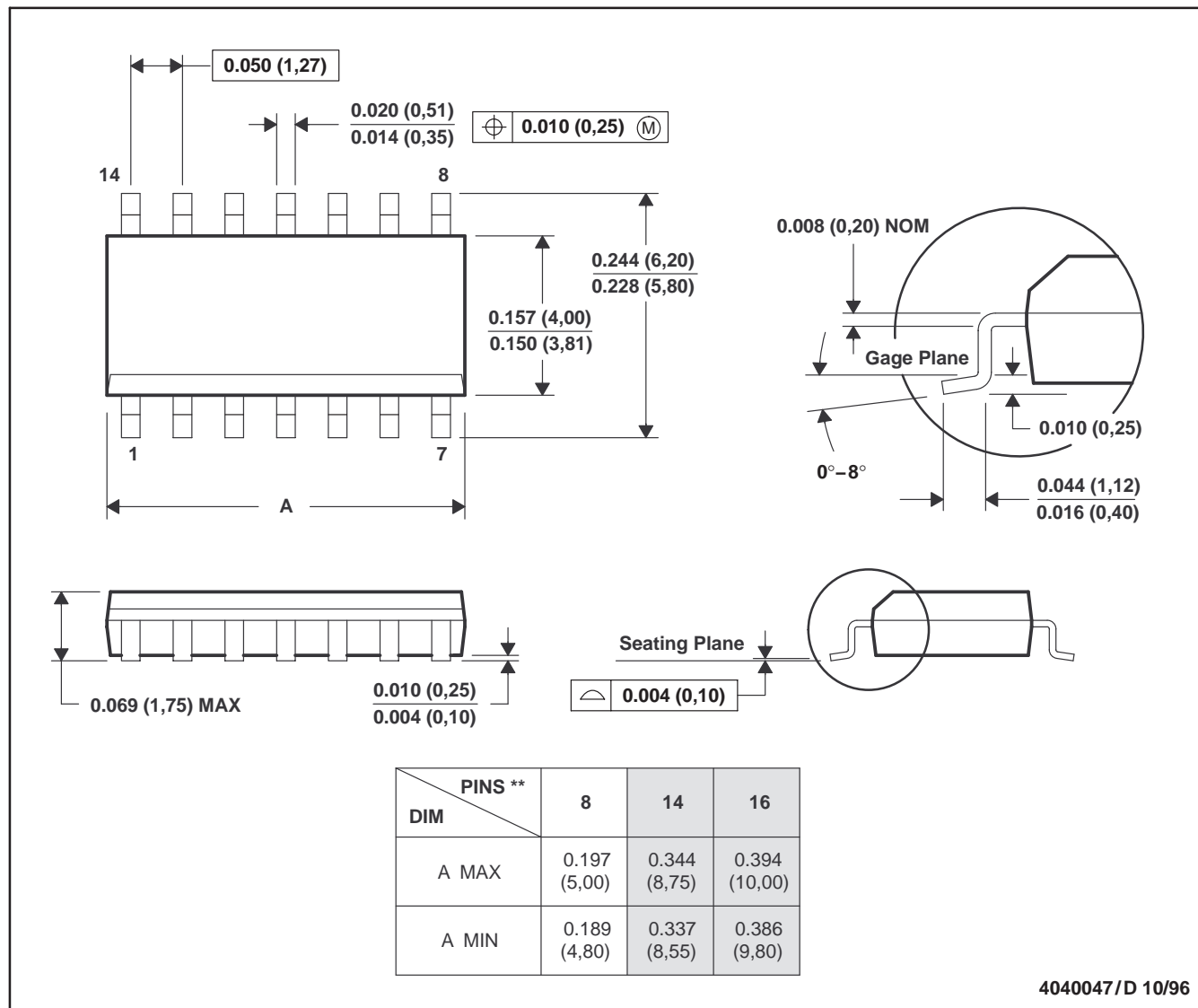
SLAS233D – JULY 1999 – REVISED JULY 2002

MECHANICAL DATA

D (R-PDSO-G)**

PLASTIC SMALL-OUTLINE PACKAGE

14 PIN SHOWN



- NOTES: A. All linear dimensions are in inches (millimeters).
 B. This drawing is subject to change without notice.
 C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).
 D. Falls within JEDEC MS-012

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

TI products are not authorized for use in safety-critical applications (such as life support) where a failure of the TI product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of TI products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by TI. Further, Buyers must fully indemnify TI and its representatives against any damages arising out of the use of TI products in such safety-critical applications.

TI products are neither designed nor intended for use in military/aerospace applications or environments unless the TI products are specifically designated by TI as military-grade or "enhanced plastic." Only products designated by TI as military-grade meet military specifications. Buyers acknowledge and agree that any such use of TI products which TI has not designated as military-grade is solely at the Buyer's risk, and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI products are neither designed nor intended for use in automotive applications or environments unless the specific TI products are designated by TI as compliant with ISO/TS 16949 requirements. Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, TI will not be responsible for any failure to meet such requirements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products

Amplifiers	amplifier.ti.com
Data Converters	dataconverter.ti.com
DSP	dsp.ti.com
Clocks and Timers	www.ti.com/clocks
Interface	interface.ti.com
Logic	logic.ti.com
Power Mgmt	power.ti.com
Microcontrollers	microcontroller.ti.com
RFID	www.ti-rfid.com
RF/IF and ZigBee® Solutions	www.ti.com/lprf

Applications

Audio	www.ti.com/audio
Automotive	www.ti.com/automotive
Broadband	www.ti.com/broadband
Digital Control	www.ti.com/digitalcontrol
Medical	www.ti.com/medical
Military	www.ti.com/military
Optical Networking	www.ti.com/opticalnetwork
Security	www.ti.com/security
Telephony	www.ti.com/telephony
Video & Imaging	www.ti.com/video
Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
Copyright © 2008, Texas Instruments Incorporated

Looking for pricing, stock, or lifecycle information?

Click below to explore more details on WIN SOURCE:

 [View TLV5625IDRG4 on WIN SOURCE](#)

 [Texas Instruments](#) Information

Optimize Your Supply Chain with WIN SOURCE Solutions

-  Global Sourcing Solution
-  Obsolete Management
-  Cost Control Management
-  Shortage Management
-  Alternative Solution
-  Excess Inventory Management